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X-ray Absorption Spectroscopy

DE GRUYTER

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About this book

Our book is primarily intended for students at the senior undergraduate and graduate levels. It should also be useful for established researchers wanting to use XAS in their research; there may even be something in this volume for practicing professionals such as beamline scientists. The chapters are designed to be read in order. The course that we teach at the University of Saskatchewan has enjoyed an incredibly wide intake, with students whose backgrounds and initial training were in physics, chemistry, geology, engineering, medicine, pharmacy, biology, toxicology, agriculture and environmental science. Because of this, we have included a fair amount of background material that may be elementary for those who have studied chemistry or physics.